TESTING CPT W ITH THE NEUTRAL {D SYSTEM

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We investigate the issue of testing CPT invariance in the neutral-D system, using D events obtained either from xed-target experiments or from a tau-charm factory. For both types of experiments we show that the expected suppression of mixing in the D system, normally viewed as a disadvantage for CP tests, allows unsuppressed measurement of certain parameters describing CPT violation. A symmetries are presented that permit the extraction of parameters for direct CPT violation in the D system and for indirect CPT violation in the K system. We also show that experiments on the neutral-D system provide an alternative means for measuring conventional indirect T violation in the kaon system.

Accepted in Rapid Communications, Physical Review D, issue of December 1995

I. Introduction

CPT invariance is believed to be a fundam ental symmetry of local relativistic point-particle eld theories [1, 2, 3, 4]. Experimental studies of CPT symmetry probe the foundations of modern particle physics, and they can therefore provide tests of certain alternatives to conventional theories. For example, one measurable signature of an underlying string theory could be a violation of CPT appearing through a mechanism ultimately traceable to string nonlocality [5, 6]. Another example is a possible CPT-violating e ect that might arise from modi cations of quantum mechanics due to quantum gravity [7, 8, 9], perhaps in the context of string theory [10].

The most stringent bound on CPT violation, which by one measure is a few parts in 10^{18} [11, 12, 13], arises from interferom etric tests in the neutral-kaon system. O ther neutral-meson systems may also provide interesting CPT bounds. For example, in the string-based scenario for CPT violation, e ects could appear at levels accessible to experiment not only in the K system but also in the B and D systems [6]. Since the corresponding sizes of any CPT violation could be di erent, it is important to bound experimentally the CPT-violating parameters in all these systems.

To date, no experimental bounds have been placed on CPT violation in the B or D systems. The feasibility of placing experimental limits on the parameters for direct and indirect CPT violation in the B system has recently been demonstrated [14]. It is plausible that analysis of existing data could already set interesting bounds, and the B factories currently under construction should provide further improvements.

In contrast, despite signi cant advances in the understanding of charm physics (for a recent proceedings, see ref. [15]), there has been as yet neither an experim ental study nor a system atic theoretical treatment of CPT violation in the D system. Indeed, m easurements of any indirect CP violation in the D system are generally viewed as infeasible. This is because the decay time for the neutral D m eson is much less than its characteristic mixing time, so any indirect CP violation is suppressed by a small mixing parameter x. A lso, the short D lifetime means that only time-integrated rates can be observed. This raises a second issue: disentangling the various T and CPT e ects so the quantities parametrizing CPT violation can be isolated. In this paper, we address the issues of suppression and disentanglement with a model-independent treatment in the context of conventional quantum mechanics. Our framework can therefore handle the string-based CPT violation discussed in refs. [5, 6]. Additional CPT-violating e ects involving some modied form of quantum mechanics might arise from the evolution of pure states into mixed ones in quantum gravity [7, 8, 9] or possibly in string theory [10]. One approach to modeling such e ects is to modify the Schrödinger equation, which introduces additional parameters. In the context of the kaon system, a simple parametrization involving three additional quantities has been suggested [16, 17]. A treatment of this topic in the present context lies outside the scope of the present paper. We restrict ourselves here to the observation that it would be of interest to generalize the present results and those of ref. [14] to incorporate possible CPT violation in the B and D system s arising from m odi cations to quantum mechanics.

To address the issue of suppression, we show that the size of the m ixing parameter x is irrelevant to the m easurement of certain parameters describing direct CPT and indirect T violation. Moreover, the suppression of indirect D -system CP violation can in fact be viewed as an advantage because the D -decay modes to kaons are then accompanied by unsuppressed and measurable indirect K -system CPT and T violation. These results indicate that CP studies in the neutral system are of experimental interest despite the small size of the mixing parameter x.

To address the issue of disentangling T and CPT e ects, we provide certain asymmetries that separate parameters describing CPT violation. In the analysis, we consider xed-target experiments producing single tagged neutralD mesons (these would also include tagged D mesons from a B factory) and experiments at a -charm factory, which would produce large numbers of correlated D $^{0}\overline{D^{0}}$ pairs from the decay of the (3770) resonance. We obtain estimates for bounds on CPT violation that could be obtained from present and future experiments of both classes.

Current experimental limits on direct CP violation in CKM -suppressed decay modes of the D meson are attaining the 10% level [18]. About 10^5 fully reconstructed charm events already exist [19], and it appears feasible to obtain about 10^8 fully reconstructed D events by the turn of the century using xed-target and factory

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experiments [20]. The analysis we present here suggests that some bounds on CPT violation m ight already be obtained from extant data and that results of experiments over the next few years would yield useful limits.

II. P relim inaries

The eigenvectors of the e ective ham iltonian for the D $^{0}-\overline{D}$ system are

$$\mathfrak{D}_{S} \mathbf{i} = \frac{p^{1}}{2} [(1 + p + p) \mathfrak{D}^{0} \mathbf{i} + (1 p p) \mathfrak{D}^{0} \mathbf{i}] ;$$

$$\mathfrak{D}_{L} \mathbf{i} = \frac{p^{1}}{2} [(1 + p p) \mathfrak{D}^{0} \mathbf{i} (1 p + p) \mathfrak{D}^{0} \mathbf{i}] :$$

$$(1)$$

The CP-violating complex parameters $_{D}$ and $_{D}$ are measures of indirect T and indirect CPT violation, respectively. The analogous parameters $_{K}$ and $_{K}$ for the K system are deneed by Eq. (1) but with the replacement D ! K.

We denote the decay rates of the physical particles D_s , D_L by $_s$, $_L$ and their masses by m_s , m_L . Useful combinations of these basic parameters are $= s_{L}$, $m = m_L m_s$, $= s_{L}$, $a^2 = m^2 + c^2 = 4$, and $b^2 = m^2 + c^2 = 4$.

In the D system, the m ixing parameter $x = 2 \text{ m} = \text{ is experimentally bounded }^2$ [21] to jxj < 0.08. The theoretical value of x is uncertain. Calculations based on standard-m odel physics [22] suggest that jxj is smaller than 10², although the presence of long-distance dispersive e ects makes accurate prediction di cult [23, 24]. However, extensions to the standard model can generate larger values of x. We therefore keep terms to order x^2 in what follows. A lso, in explicit estimates, we take

' m for simplicity. A mong the elects of scaling relative to m is the scaling of Re $_{\rm D}$ relative to Im $_{\rm D}$. In any event, any such elects are straightforward to calculate from the general expressions we provide below.

Our analysism akes use of two di erent classes of D-m eson decays. The rst class, called sem ileptonic-type f decays, includes the usual sem ileptonic decays along with a

¹Throughout this paper we assume sm all CP violation, im plying sm all T and CPT violation, and we neglect term s that are higher-order in sm all quantities. Our phase conventions are discussed in m ore detail in refs. [6, 14].

 $^{^{2}}$ The analysis leading to this result assumes negligible CPT violation. The value of x could be larger if signi cant CPT violation is present. Our assumption of small CP violation makes it consistent to take x small also.

special class of other m odes D⁰! f for which there is no low est-order weak process allowing a signi cant contam ination of either $\overline{D^0}$! f or D⁰! f. The currently observed nal states f of this type with signi cant branching ratios are the usual sem ileptonic ones and those that involve production of a \overline{K} (892)⁰ along with other non-strange m esons. For the remaining observed m odes, a CKM -suppressed process contributes to the contam inating transitions. The second class, called sem ileptonictype $\overline{K^0}X$ decays, includes all nal states that contain a $\overline{K^0}$ but do not contain a $\overline{K^0}$. This m eans there is no low est-order weak process for $\overline{D^0}$! $\overline{K^0}X$ or D⁰! $K^0\overline{X}$. Note that the above requirem ents for both types of decay are m ore stringent than in posing only that the conjugate m ode is CKM suppressed. For example, the state f K⁻⁺ is excluded.

III. Fixed-Target Experim ents

This section presents our analysis of rates and asymmetries for xed-target experiments. We rst consider integrated decay rates involving sem ileptonic-type f decays. The associated transition amplitudes can be parametrized as [25, 26]:

$$\begin{split} & \text{hf Jf } \stackrel{0}{\mathcal{D}} \stackrel{0}{\mathbf{i}} = F_{f} \begin{pmatrix} 1 & y_{f} \end{pmatrix} ; & \text{hf Jf } \stackrel{1}{\mathcal{D}} \stackrel{0}{\mathbf{j}} \stackrel{1}{\mathbf{i}} = \mathbf{x}_{f} F_{f} \begin{pmatrix} 1 & y_{f} \end{pmatrix} ; \\ & \text{hf Jf } \stackrel{1}{\mathcal{D}} \stackrel{0}{\mathbf{j}} \stackrel{1}{\mathbf{j}} \stackrel{0}{\mathbf{j}} \stackrel{1}{\mathbf{j}} = \overline{\mathbf{x}}_{f} F_{f} \begin{pmatrix} 1 + y_{f} \end{pmatrix} ; & (2) \end{split}$$

The independent quantities F_f , y_f , x_f and \overline{x}_f are all complex. The latter two vanish if C = Q, so in what follows we treat them as small. If T invariance holds, all four quantities are real. If CPT invariance holds, $x_f = \overline{x}_f$ and $y_f = 0$. The parameter y_f therefore characterizes direct CPT violation in the decay to f and as such is of particular interest here.

T in e-integrated rates for sem ileptonic-type f decays of D m esons can be expressed in term s of the above quantities. D enote by \mathcal{D} (t) i the tim e-evolved state arising from the state \mathcal{D}^{0} i at t = 0 and by $\overline{\mathcal{D}}$ (t) i the state arising from $\overline{\mathcal{D}^{0}}$ i at t = 0. Then, there are four tim e-integrated rates of interest, given by

$$R_{f} = \int_{0}^{Z_{1}} dt f_{f} f_{f} (t) i f$$

$$= \frac{F_{f}}{2} \int_{2}^{h} \left(\frac{1}{s_{L}} + \frac{1}{b^{2}}\right) (1 \quad 2Rey_{f}) \quad \frac{2}{s_{L}}Re(2_{D} + x_{f})$$

$$= \frac{4}{b^{2}} Im (2_{D} + x_{f})^{i}; \qquad (3)$$

$$R_{\overline{f}} = \int_{0}^{2} dt j \overline{f} \overline{f} \overline{f} p (t) i \overline{f}$$

$$= j \frac{F_{f}}{2} j^{h} (\frac{1}{s_{L}} - \frac{1}{b^{2}}) (1 - 2Re(2_{D} - y_{f})) - \frac{2}{s_{L}} Re \overline{x}_{f}$$

$$- \frac{4 m}{b^{2}} \operatorname{Im} \overline{x}_{f}^{i} ; \qquad (5)$$

$$\overline{R}_{f} = \int_{0}^{Z_{1}} dt f_{f} \overline{f} \overline{p} (t) i f = R_{\overline{f}} (y_{f} ! y_{f}; p! p; \overline{x}_{f} ! x_{f}) :$$
(6)

The expressions for the rates $\overline{R_f}$ and $\overline{R_f}$ are obtained by making the indicated replacements in R_f and $R_{\overline{f}}$, respectively.

From these rates, we can extract an asym m etry providing inform ation about direct CPT violation. It is

$$A_{f} = \frac{R_{f} \quad \overline{R}_{\overline{f}}}{R_{f} + \overline{R}_{\overline{f}}}$$

$$= 2Rey_{f} \quad \frac{1}{(b^{2} + s_{L})}^{h} \quad b^{2} (4Re_{D} + Re(x_{f} \quad \overline{x}_{f}))$$

$$+ 2m_{SL} (4Im_{D} + Im(x_{f} + \overline{x}_{f}))^{i}$$

$$' \quad 2Rey_{f} \quad x [Re_{D} + \frac{1}{4}Re(x_{f} \quad \overline{x}_{f}) + 2Im_{D} + \frac{1}{2}Im(x_{f} + \overline{x}_{f})] : (7)$$

The rst term in this expression is a measure of direct CPT violation in the D system. The remaining terms are suppressed by the mixing parameter x. If we further assume that violations of C = Q are independent of CP violation, then $x_f = \overline{x}_f$. This makes the asymmetry A_f independent of the particular nal state.

Another asymmetry can be formed as follows:

$$A_{f}^{0} = \frac{\overline{R}_{f}}{\overline{R}_{f} + R_{\overline{f}}} = 2Re(2_{D} - y_{f}) :$$
(8)

In deriving the latter expression, we have taken violations of C = Q to vanish for simplicity. This asymmetry is of lesser interest than that of Eq. (7) because the

rates them selves are suppressed by at least one power of x. This means the statistics required for observation of this asymmetry are increased by a factor of at least $1=x^2$, so we disregard it in the following.

N ext, we consider integrated decay rates involving sem ileptonic-type $\overline{K^{0}X}$ decays. D e ne transition amplitudes for these processes analogous to the de nitions in Eq. (2):

$$h\overline{K}^{0} \mathfrak{T} \mathfrak{D}^{0} \mathfrak{i} = F_{K} (1 \quad Y_{K}) \quad ; \quad h\overline{K}^{0} \mathfrak{T} \mathfrak{D}^{0} \mathfrak{i} = x_{K} F_{K} (1 \quad Y_{K}) \quad ;$$
$$hK^{0} \mathfrak{T} \mathfrak{D}^{0} \mathfrak{i} = F_{K} (1 + Y_{K}) \quad ; \quad hK^{0} \mathfrak{T} \mathfrak{D}^{0} \mathfrak{i} = \overline{x}_{K} F_{K} (1 + Y_{K}) \quad : \qquad (9)$$

To simplify notation, in the above amplitudes the symbols hK^{0} j and $h\overline{K}^{0}$ j are used to represent the full multiparticle nalstates containing the corresponding K m eson. The complex parameters x_{K} , \overline{x}_{K} , F_{K} , and y_{K} depend on the speci c nal state involved. They have the same properties under T and CPT invariance as the analogous parameters for sem ileptonic-type f decays. Note that x_{K} and \overline{x}_{K} are taken to be sm all because the associated amplitudes have no lowest-order weak contribution.

Observable nal states involve K_S and K_L rather than K⁰ and \overline{K}^0 . We use the notation hK_S jand hK_L jto represent the linear combinations of the sem ileptonic-type \overline{K}^0 X nal state and its charge conjugate given by the kaon equivalent of Eq. (1). With these amplitudes, there are again four integrated rates:

$$= \frac{Re^{2}F_{K}h^{2}}{2}\frac{h}{L} \frac{1}{L} (\frac{2}{L} \frac{b^{2}}{b^{2}})Re(_{D} + _{D} + \frac{1}{2}x_{K}) (\frac{2}{L} + \frac{b^{2}}{b^{2}})Re\frac{1}{2}\overline{x}_{K}$$

$$\overline{b}^{2} \operatorname{Re}\left(_{K} \quad _{K} + y_{K}\right) + \frac{2 m}{b^{2}} (\operatorname{Im}\left(_{K} \quad _{K} + _{D} + _{D} + \frac{1}{2} (\overline{x}_{K} + x_{K})\right) + \frac{\overline{b}^{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})) + \frac{1}{2} (\overline{x}_{K} + x_{K}) + \frac{1}{2} (\overline{x}_{K} + x_{K})$$

In the above a double arrow \$ is used to indicate an interchange of parameters rather than a substitution.

From these integrated rates, two useful asymmetries can be constructed:

$$A_{S} = \frac{R_{S} R_{S}}{R_{S} + R_{S}}$$

$$= 2(1 \frac{S}{2b^{2}})Re(D_{D}) \frac{S}{2b^{2}}Re(\overline{x}_{K} x_{K}) + \frac{S}{b^{2}}Re(R + R + Y_{K})$$

$$' 2(1 + \frac{1}{2}x x^{2})Re(R + R + Y_{K}) \frac{1}{2}(\overline{x}_{K} x_{K}))$$

$$x(1 2x)Re(D_{D}); (14)$$

$$A_{L} = \frac{\overline{R}_{L} R_{L}}{\overline{R}_{2} + R_{2}}$$

$$R_{L} + R_{L} = 2(1 \frac{L}{2b^{2}})Re(_{D} + _{D}) + \frac{L}{2b^{2}}Re(\overline{x}_{K} - x_{K}) + \frac{L}{b^{2}}Re(_{K} - _{K} + y_{K})$$

$$(2(1 \frac{1}{2}x - x^{2})Re(_{K} - _{K} + y_{K} + \frac{1}{2}(\overline{x}_{K} - x_{K})) + x(1 + 2x)Re(_{D} + _{D}) : (15)$$

Their di erence gives the combination

$$A_{L} \quad A_{S} = 4Re_{K} + 2Re(\overline{x}_{K} \quad x_{K}) + 2xRe(D_{K} \quad y_{K}) + 4x^{2}Re(D_{K} + \frac{1}{2}(\overline{x}_{K} \quad x_{K})) ; (16)$$

while their sum is

$$A_{L} + A_{S} = 4Re(_{K} + y_{K}) + 2xRe(_{D} + _{K} \frac{1}{2}(\overline{x}_{K} - x_{K})) + 4x^{2}Re(_{D} - _{K} - y_{K}) : (17)$$

Assuming violations of C = Q are independent of CPT violation, the terms containing $\overline{x}_K = x_K$ vanish. In any event, for negligible mixing x these expressions

reduce to their st term s.

IV. Experiments at a Tau-Charm Factory

In this section, we turn to a discussion of rates and asymmetries for experiments that are feasible at a tau-charm factory. Several relevant integrated rates arise. One is the time-integrated rate $(f_1; f_2)$ for the decay of the correlated $D^{0}\overline{D^{0}}$ pair into states f_1 and f_2 . In discussing other rates, it is convenient to separate the rate $(f_1; f_2)$ into the component $+(f_1; f_2)$ for which the decay into f_1 occurs rst and the component

 $(f_1; f_2)$ for which f_2 occurs rst. Then, another useful quantity is the inclusive rate $_{incl}^+(f_1)$, obtained by summing $^+(f_1; f_2)$ over nalstates f_2 . We nd

$$(f_{1}; f_{2}) = \frac{1}{2} \int_{X}^{h} \dot{p}_{1S} a_{2L} \dot{f} + \dot{p}_{1L} a_{2S} \dot{f} - \frac{s}{b^{2}} (a_{1S} a_{2L} a_{1L} a_{2S} + cc:)^{i} ; (18)$$

$$+ \int_{x}^{h} (f_{1}; f_{2}) = \frac{1}{2} \int_{X}^{f_{2}} \dot{p}_{1S} \dot{f} + \dot{p}_{1L} \dot{f} - 2[a_{1S} a_{1L} (Re_{D} + iIm_{D}) + cc:]^{i} ; (19)$$

where the transition am plitudes are de ned as

$$a_{s} = hf \mathcal{T} \mathcal{D}_{s} i; \quad a_{L} = hf \mathcal{T} \mathcal{D}_{L} i; \quad (20)$$

Further details about calculating these rates m ay be found in refs. [6, 14].

We begin by considering sem ileptonic-type f decays. The parameter $R ey_f$ describing direct CPT violation can be extracted from the above rates using the asymmetry

$$A_{f}^{+} = \frac{\frac{+}{\operatorname{incl}}(f) + \frac{+}{\operatorname{incl}}(\overline{f})}{\frac{+}{\operatorname{incl}}(f) + \frac{+}{\operatorname{incl}}(\overline{f})} = 2\operatorname{Rey}_{f} :$$
(21)

W e see that this asymm etry provides a test of direct CPT violation that is independent of any T or indirect CPT violation.

O ther asymmetries with suppressed component rates or suppressed magnitudes can be examined by restricting attention to semileptonic-type f decays in both channels. An asymmetry isolating parameters for indirect CPT violation in the D system can be constructed as

$$A_{f;\overline{f}} = \frac{+(f;\overline{f}) + (f;\overline{f})}{+(f;\overline{f}) + (f;\overline{f})}$$

$$= 4 \frac{b^{2} \text{ Re } p + 2 \text{ m } s \text{ Im } p}{(b^{2} + s \text{ I})}$$

' x (Re p + 2 Im p) : (22)

The derivation assumes violations of C = Q are independent of CP violation, so that $x_f = \overline{x}_f$. The x-dependence of the result means that the number of events required to measure a non-zero value for $A_{f,\overline{f}}$ is scaled by $1=x^2$. Another possible asymmetry is

$$A_{f;\overline{f}}^{\text{tot}} = \frac{(f;f) \quad (\overline{f};\overline{f})}{(f;f) + (\overline{f};\overline{f})} = 4\text{Re}\left(\sum_{D} y_{f}\right) : \qquad (23)$$

In this case, the rates them selves are suppressed by a factor of x^2 , so the required statistics are scaled by $1=x^4$.

Next, we consider the case with one channel involving a sem ileptonic-type K_SX or K_LX decay while the other channel involves a sem ileptonic-type f decay. Transition amplitudes for the $\overline{K}X$ decays are de ned in Eq. (9). With these, we obtain:

$$\overset{\mathrm{hK}_{\mathrm{S}}}{=} \frac{\overset{\mathrm{hK}_{\mathrm{S}}}{\operatorname{f}} \overset{\mathrm{f}}{\operatorname{p}_{\mathrm{S}}} \overset{\mathrm{i}}{\mathrm{i}} \frac{1}{\operatorname{hK}_{\mathrm{S}}} \overset{\mathrm{f}}{\operatorname{f}} \overset{\mathrm{f}}{\operatorname{p}_{\mathrm{S}}} \overset{\mathrm{i}}{\mathrm{i}} \frac{1}{\operatorname{ReF}_{\mathrm{K}}} \left(\overset{\mathrm{K}_{\mathrm{K}}}{\operatorname{ReF}_{\mathrm{K}}} - \frac{1}{2\operatorname{ReF}_{\mathrm{K}}} \left(\overset{\mathrm{K}_{\mathrm{K}}}{\operatorname{ReF}_{\mathrm{K}}} - \frac{1}{2\operatorname{ReF}_{\mathrm{K}}} \left(\overset{\mathrm{K}_{\mathrm{K}}}{\operatorname{ReF}_{\mathrm{K}}} - \frac{1}{2\operatorname{ReF}_{\mathrm{K}}} \right) \right)$$

$$+ i \frac{\operatorname{Im}_{\mathrm{ReF}_{\mathrm{K}}}}{\operatorname{ReF}_{\mathrm{K}}} \overset{\mathrm{h}}{1} - i \frac{\operatorname{Im}_{\mathrm{ReF}_{\mathrm{K}}}}{\operatorname{ReF}_{\mathrm{K}}} \left(\overset{\mathrm{K}_{\mathrm{K}}}{\operatorname{R}} + \overset{\mathrm{I}}{\operatorname{D}} - \overset{\mathrm{K}_{\mathrm{K}}}{\operatorname{R}} + \overset{\mathrm{I}}{\operatorname{D}} \right)$$

$$- \frac{1}{2\operatorname{ReF}_{\mathrm{K}}} \left(\overset{\mathrm{K}_{\mathrm{K}}}{\operatorname{F}}_{\mathrm{K}} + \overline{\operatorname{X}}_{\mathrm{K}}} \overset{\mathrm{F}}{\operatorname{F}}_{\mathrm{K}} \right) + i \frac{\operatorname{Im}_{\mathrm{ReF}_{\mathrm{K}}}}{\operatorname{ReF}_{\mathrm{K}}} \overset{\mathrm{I}}{\operatorname{ReF}_{\mathrm{K}}} ; \qquad (24)$$

 ${}_{K_{L}} \qquad \frac{hK_{L} \text{T} \text{D}_{S} \text{i}}{hK_{L} \text{T} \text{D}_{L} \text{i}} = {}_{K_{S}} \left({}_{D} ! {}_{D} \text{;}_{K} ! {}_{K} ! {}_{K} \text{;} \overline{x}_{K} ! {}_{K} \text{;} \overline{x}_{K} ! {}_{K} \text{;} \overline{x}_{K} \right) : (25)$

U sing these, we calculate two useful rate asymmetries:

$$A_{f,K_{S}} = \frac{(f;K_{S}) \quad (f;K_{S})}{(f;K_{S}) + (\overline{f};K_{S})}$$
$$= 2Re(D_{D} \quad y_{f} \quad D) \quad \frac{2_{S} L}{b^{2}}Re(K_{S}); \qquad (26)$$

and

$$A_{f;K_{L}} \quad A_{f;K_{S}} (K_{S} ! K_{L}) = A_{f;K_{S}} (D_{L} ! D; K_{S} ! K_{L}) :$$
(27)

These two asymmetries have been derived under the assumption that violations of C = Q are independent of CPT violation, so that $x_f = \overline{x}_f$ and $x_K = \overline{x}_K$. Since

In F_{K} controls the direct T violation in these processes, we have also treated it as a small quantity. This latter assumption is made more plausible by the current experimental bounds at about the 10% level on parameters describing direct T violation [18]. The above expressions can be approximated for the D system as

$$A_{f,K_{S}}$$
 ' $2Rey_{f} + 2Re(_{K} + _{K} + y_{K}) + \frac{5}{2}x^{2}Re(_{D} _{D})$ (28)

$$A_{f,K_{L}}$$
 ' $2Rey_{f} + 2Re(_{K} + y_{K}) + \frac{5}{2}x^{2}Re(_{D} + _{D})$ (29)

The di erence between the two above equations is a function of CPT-violating parameters:³

$$A_{L,S} \quad A_{f,K_L} \quad A_{f,K_S} ' \quad 4Re_K + 5x^2Re_D :$$
(30)

The coe cient of Re $_{\rm D}$ is of order no larger than 10 4 . The second term can therefore be neglected, and we are left with an asymmetry measuring the parameter Re $_{\rm K}$ for indirect CPT violation in the K system. This result is independent of either of the nal states, so the statistics can be made more favorable by summing over the class of relevant nal states.

The sum of the two asymmetries gives the combination

$$A_{L:S}^{+} = A_{f;K_{L}} + A_{f;K_{S}} ' 4Re(_{K} + y_{K} + y_{f}) + 5x^{2}Re_{D}$$
 : (31)

Here, the parameter measuring indirect T violation in the neutral-D system is suppressed by the factor x^2 , thereby producing an asymmetry measuring the combination Re($_{K}$ + y_{K} y_f). Note that this quantity depends on both nalstates through the direct CPT-violation parameters y_{K} and y_{f} .

V.Estim ates of Bounds Attainable

The asymmetries given in the previous two sections demonstrate that CPT information can be extracted from the D system. Next, we investigate the bounds attainable using these asymmetries. For xed-target experiments, we estimate the

³ It can be shown that Eq. (30) is in fact correct to term s simultaneously quadratic in Im F_K and linear in $_D$ or $_K$ even if the constraint of sm all direct T violation is relaxed.

num ber of D⁰ particles required to reduce the error in a given asym m etry to one standard deviation. For m easurem ents at a tau-charm factory, we estim ate the num ber of (3770) events required for a sim ilar precision. The analysis follows the m ethods presented in refs. [27, 6, 14].

A ssum ing a binom ial event distribution and a general asymmetry $A = (N_+ N_-) = (N_+ + N_-)$, observation of a nonzero hA i at the N_level requires an expected number of events $hN_+ i = N^2 (1 + hA i) (1 - hA i^2) = 2hA i^2$. Conversion of this to an expected number of D⁰ events required in a xed-target experiment involves multiplication by the inverse branching ratio for the D⁰ decay into the relevant nal state. Similarly, conversion to an expected number of (3770) events required in a tau-

(3770) into two neutralD m esons, and by the inverse branching ratio for the further decays into the relevant nal states. Interference e ects in the correlated decays can be neglected because T and CPT violation is assumed small.

We rst consider the asymmetries arising from the xed-target experiments discussed in section III.

For the asymmetry A_f given by Eq. (7), assuming su cient suppression by x, the number of D⁰ events required to measure Rey_f to within one standard deviation is

$$N_{D} (Rey_{f})' \frac{1}{8^{-2}BR (D^{0}! f)}$$
 : (32)

The asymmetries A_s and A_L given in Eqs. (14) and (15) have the same general form as A_f , so the number of D⁰ events needed to reduce the error in either to one standard deviation is given by an expression analogous to Eq. (32). However, the interesting information is contained in their sum and difference A_L A_s given in Eqs. (17) and (16). Combining errors in quadrature gives the number of D particles required to reduce the error in A_L A_s to one standard deviation as

$$N_{D} (A_{L} A_{S})' \frac{1}{^{2}BR (D^{0} ! \overline{K^{0}} + any)} :$$
(33)

In particular, for small x we obtain

$$N_{D} (Re_{K})' N_{D} (Re(_{K} + Y_{K}))' \frac{1}{16^{2}BR (D^{0}! \overline{K^{0}} + any)} : (34)$$

The branching ratios relevant to the above neutral-D decay are typically of the order of several percent. D isregarding (potentially in portant) experimental e ects, the present availability of 10^5 reconstructed events suggests that bounds of the order of 10^2 to 10^3 could be placed on both direct CPT violation in the D system (using Eq. (32)) and indirect CPT violation in the K system (using Eq. (34)). D irect bounds at this level would already be of interest, and the possibility of substantially increased num bers of reconstructed D events suggest signi cant in provem ent could be expected in the near future.

Next, we turn to bounds arising from experiments at a tau-charm factory.

The parameter Rey_f determining direct CPT violation can be measured using A_{f}^{+} given in Eq. (21). The second nal state is unrestricted, so it suces to multiply by the inverse branching ratio for the process D⁰! f. However, the asymmetry involves only those events for which the decay into foccurs rst. Since _S _L in the D system, events with the decay into foccurring rst are roughly equally frequent as those with the decay occurring second. An extra factor of two is therefore needed. Collecting these factors, we nd that the number N ₍₃₇₇₀₎ (Rey_f) of (3770) events needed to reduce the error in Rey_f to within one standard deviation is

N ₍₃₇₇₀₎ (Rey_f)
$$' \frac{1}{2^{2}BR(D^{0}! f)}$$
 : (35)

The combination $A_{L,S}$ of asymmetries given by Eq. (30) measures Re $_{K}$, the parameter for indirect CPT violation in the K system. The independence of $A_{L,S}$ on the speci c sem ileptonic-type f decay means that the corresponding branching ratios can be added. Using ref. [21], we get $_{f}^{P}$ BR (D $_{i}^{0}$! f) ' 27%. The quantity $A_{L,S}$ is also independent of the speci c nal-state particles that appear with the K s or K $_{L}$ in the other channel in a general sem ileptonic-type $\overline{K^{0}X}$ nal state. Summing over these gives $_{X}^{P}$ BR (D $_{i}^{0}$! $\overline{K^{0}X}$) ' 38%. Furthermore, in determining the nalresult it is reasonable to take as roughly equal the errors in the two asymmetries $A_{f,K_{L}}$ and $A_{f,K_{S}}$. Collecting this information, we nd that the number N (3770) (Re $_{K}$) of (3770) events needed to reduce the error in Re $_{K}$ to within one standard deviation

is

N (3770) (Re K)
$$' \frac{1}{2}$$
 : (36)

This result is somewhat more favorable than the corresponding xed-target result, Eq. (34).

The sum of the asymmetries $A_{L,S}^+$ measuring the combination $\text{Re}(_{K} + y_{K} - y_{f})$, given in Eq. (31), depends on both nalstates. O there ise the estimation is the same as for $A_{L,S}^-$ given above. Therefore, we get

$$N_{(3770)} (\text{Re}(_{K} + y_{K} - y_{f}))' \frac{1}{8^{2}\text{BR}(D^{0}! \overline{K}^{0} + \text{any})\text{BR}(D^{0}! f)} : (37)$$

In this case, the result is less favorable than the corresponding xed-target results, Eq. (32) and (34), because two (relatively small) branching ratios enter instead of one.

Equations (34) and (37) involve $_{\rm K}$, which measures indirect T violation in the K system, along with the parameters $y_{\rm f}$ and $y_{\rm K}$ for direct CPT violation in the D system. These equations can therefore be used either as measurements of direct CPT violation if $_{\rm K}$ is taken from other experiments in the K system, or as measurements providing a new check on $_{\rm K}$ if CPT violation is assumed small. In the latter case, the possibility of 10⁸ reconstructed D events could in principle produce a measurement of $_{\rm K}$ to 10⁴ or so.⁴

In the event that the magnitude of x is relatively close to the current experimental limit, as could happen in extensions of the standard model, it may be possible to use the above asymmetries to extract the parameters Re_{D} and Im_{D} describing D - system CPT violation and therefore to provide a test of the string-inspired relation [6]

$$\operatorname{Re}_{D} = \frac{2 \text{ m}}{100 \text{ m}} \text{ m} \text{ m}$$

For illustrative purposes, we now neglect y_f , x_f , \overline{x}_f , and term s involving second and higher powers of x in the asymmetries, and we suppose _K is known to su cient precision from other experiments. From Eq. (7) for the asymmetry A_f , summing over nal states f we nd

$$N_{D} (Re_{D} + 2Im_{D})' \frac{3}{2x^{2}}' \frac{600}{2};$$
 (39)

 $^{^{4}}$ The possibility of measuring _K using reconstructed charged D events has recently been suggested [28].

where in the nalform we have taken a value x' 0:05 close to the maximum possible. Similarly, summing over nalstates \overline{KX} in Eq. (17) gives

$$N_{D} (Re_{D})' \frac{1}{2x^{2}}' \frac{200}{2}$$
 : (40)

Finally, sum ming over nal states in Eq. (22) gives

N ₍₃₇₇₀₎ (Re _D + 2Im _D) '
$$\frac{9}{x^2 2}$$
 ' $\frac{3600}{2}$: (41)

These equations show that both Re $_{\rm D}$ and Im $_{\rm D}$ can in principle be extracted if conditions are favorable. For this purpose, xed-target experiments are somewhat better from the theoretical view point. Under these circum stances, interesting bounds could already be placed on $_{\rm D}$ with existing data.

VI.Summary

In this paper, the possibility of testing CPT invariance in the neutral-D system has been exam ined. W e give asymmetries relevant to this issue that can be obtained from data taken at present and future xed-target and factory experiments. They permit the determination of certain parameters governing CPT violation in the D and K systems. Unsuppressed measurements of direct D -system CPT violation are feasible. Moreover, suppressed measurements of indirect K -system CPT violation possible too. Under particularly favorable circum stances, indirect D -system CPT violation may also be measurable.

In the xed-target case, assuming smallx, Eq. (7) gives the parameter Rey_{f} controlling direct CPT violation in the D system. Similarly, Eq. (16) gives Re_{K} , involving indirect K -system CPT violation, and Eq. (17) gives the combination $\operatorname{Re}(_{K} + y_{K})$ of quantities measuring indirect K -system T violation and direct D -system CPT violation. All these asymmetries also contain terms higher than second order in the smallm ixing parameter x, involving indirect CP violation in the D system.

For experiments at a tau-charm factory, Eq. (21) gives Rey_{f} , Eq. (30) gives Re_{K} , and Eq. (31) gives the combination $\operatorname{Re}(_{K} + y_{K} - y_{f})$. Again, parameters for indirect CPT violation in the D system are suppressed by some power of x. The only asymmetries requiring knowledge of the sign of the time dierence between the two decays of the correlated pair are those in Eqs. (21) and (22).

For both types of experiment, excluding possible background or acceptance issues, estimates of the bounds attainable are given in section 4. From a purely theoretical perspective, xed-target experiments are preferable for measuring direct CPT violation because only one decay channel is involved. In contrast, experiments at a tau-charm factory are preferable for measuring indirect K -system CPT violation because the correlations between the D pairs make possible a sum over decay channels. In any event, interesting bounds on various types of CPT violation are attainable in the neutral-D system, using data already existing or likely to become available within a few years.

A cknow ledge ent. This work was supported in part by the United States D epartment of Energy under grant number $D \in FG 02-91 \in R40661$.

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